

Notice of References Cited	Application/Control No. 10/673,247	Applicant(s)/Patent Under Reexamination YAMAKAWA ET AL.	
	Examiner Binh X. Tran	Art Unit 1765	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,495,413	12-2002	Sun et al.	438/240
	B	US-6,194,228	02-2001	Fujiki et al.	438/3
	C	US-			
	D	US-			
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	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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